

WEST Search History

DATE: Sunday, April 20, 2003

<u>Set</u> <u>Name</u> side by side	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
	<i>DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>		
L31	(iNTERNATIONAL BUSINESS MACHINES or IBm)and (signal or data) near (size or length\$7 or long or wid\$7) near (different or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or variable or varY\$3) same test\$3 and (cell or row or column or matri\$3 or array) and (pattern or vector or sequen\$7)	8	L31
L30	(signal or data) near (size or length\$7 or long or wid\$7) near (different or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or variable or varY\$3) same test\$3 same (cell or row or column or matri\$3 or array) same (pattern or vector or sequen\$7)	2	L30
L29	IBM and (signal or data) near (size or length\$7 or long or wid\$7) with(differ\$5 or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same test\$3	44	L29
L28	L27 not L24	9	L28
L27	(signal or data) near (size or length\$7 or long or wid\$7) with(differ\$5 or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same test\$3 same (cell or row or column or matri\$3 or array) same (pattern or vector or sequen\$7)	17	L27
L26	(signal or data) near (size or length\$7 or long or wid\$7) with(differ\$5 or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same test\$3 same (cell or row or column or matri\$3 or array) same pattern	11	L26
L25	('6499119')[ABPN1,NRPN,PN,TBAN,WKU]	2	L25
L24	(signal or data) near (size or length\$7 or long or wid\$7) with(different or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same test\$3 same (cell or row or column or matri\$3 or array) same pattern	8	L24
L23	('6084809')[ABPN1,NRPN,PN,TBAN,WKU]	2	L23
L22	('20020116673')[ABPN1,NRPN,PN,TBAN,WKU]	2	L22
L21	L20 and data width with(different or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same test\$3 same (cell or row or column or matri\$3 or array) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7)	5	L21
L20	L19 and data width same test\$3 same (cell or row or column or matri\$3 or array) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7)	38	L20
L19	data width same test\$3	178	L19
L18	('20020116673')[ABPN1,NRPN,PN,TBAN,WKU]	2	L18

L17	L16 and data width same test\$3	1	L17
L16	L15 or L14 or L13	38	L16
L15	ROWLAND near JEREMY	7	L15
L14	OUELLETTE near MICHAEL	27	L14
L13	ADAMS near DEAN	10	L13
L12	L11 not L10	5	L12
L11	L5 and data near (width or size or length)	6	L11
	L5 and (read\$3 with writ\$4) same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same (cell or row or column or matri\$3)		
L10	L5 and (read\$3 with writ\$4) same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same (row or column or matri\$3)	4	L10
L9	L5 and (read\$3 with writ\$4) same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3) same (row or column or matri\$3)	2	L9
L8	('NA9008145')[ABPN1,NRPN,PN,TBAN,WKU]	1	L8
	L5 and (read\$3 near address\$3) same writ\$4 same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)		
L7	L5 and (read\$3 near address\$3) with writ\$4 same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)	1	L7
	L5 and (read\$3 near address\$3) with writ\$4 same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)		
L6	L4 and (read\$3 with writ\$4) same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)	0	L6
	L4 and (read\$3 with writ\$4) same (input with output) same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)		
L5	L3 and input with output same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)	28	L5
	L3 and input with output same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)		
L4	L3 and input with output same (test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)	366	L4

	long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)		
L3	(test\$3 or inspect\$4 or check\$4 or debug\$4 or verif\$7 or diagno\$5 exerci\$4 or stimul\$7) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or semi conduct\$7 or memor\$7 or stor\$4 or register\$4 or array) same (size or length\$7 or long or wid\$7) near2 (different or un\$1equal\$3 or dissimilar or low\$4 or slow\$3 or high\$3 or first\$3 or second\$3 or plural\$3 or multip\$5 or fast\$3)	5632	L3
L2	('6507924')[ABPN1,NRPN,PN,TBAN,WKU]	1	L2
L1	(write or read)with (size or length\$7 or long or wid\$7) near (different or un\$1equal\$3 or dissimilar or first\$3 or second\$3 or variable or varY\$3) same test\$3 same (cell or row or column or matri\$3 or array) and (pattern or vector or sequen\$7)	6	L1

END OF SEARCH HISTORY